Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/693,909	UMESH ET AL.	
Examiner	Art Unit	
DANH C. LE	2683	

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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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Inventor Name Search (Check for Double Patent) EAST Search (USP, USPUB) EAST Search (DERWENT, EPU, JPO)	7/29/05 7/30/05 7/31/05	D(L		
Lee Nguyen (455) Hien Vuong (455) Interference Search		}		